



JT-6 (7777*6)

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PC Ano 5
A
7/28/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: NADIM JONI SHAH ET AL.)
SERIAL NO. 09/742,470) ART UNIT: TO BE ASSIGNED
FILED: DECEMBER 21, 2000) EXAMINER: TO BE ASSIGNED
FOR: TECHNIQUE TO EXAMINE AN OBJECT)

Asst. Commissioner for Patents

Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS FIRST-CLASS MAIL IN AN ENVELOPE ADDRESSED TO: ASST. COMMISSIONER FOR PATENTS, WASHINGTON D.C. 20231 ON THIS
23rd DAY OF April 2001. BY: Carlo A. McPhayes

PRELIMINARY AMENDMENT

Sir:

Prior to fee calculation and examination please amend the above-identified application as follows.

In the Claims

Please cancel claims 1-8.

Please add the following new claims.

- Sub B1*
- A*
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- 9. A process to examine at least one object, which comprises detecting properties of the object by various measurements within a spatial-frequency space formed by spatial frequencies, wherein said various measurements are taken in overlapping areas of the spatial-frequency space and in additional areas of the spatial-frequency space that differ from each other.
 - 10. The process according to claim 9, wherein said measurements of the areas take place with at least three different detection rates of occurrence.
 - 11. The process according to claim 9, wherein said areas that overlap cover a central region of the spatial-frequency space.
 - 12. The process according to claim 9, wherein the additional areas in the spatial-frequency space are at a distance from each other that is greater than their spatial-frequent extension in the direction of this distance.